

Design of a Low Power SRAM Cell by Tanner Tool 45 NM

Yashwant Singh Parihar¹, Ghansyam Jangid²

¹M.Tech Scholar, Gyan Vihar University, Jaipur, Rajasthan, India

² Assistant professor, E.C.E Deptt., Gyan Vihar University, Jaipur, Rajasthan, India

Abstract:- The absorption of power & SRAM's speed are major concern which followed several designs in accordance to the minimal absorption of power. The main concern of this document is on decadence of power while operation of Write is executed in 6-T CMOS SRAM also while operation of read as well. In this paper, an extra transistor is invaded in cell of SRAMs which will be regulate total capacitance while execution of read & write operations & also optimize the capacitance so eventually leads to bring down decadence in power. In this document we mainly focus on decadence of power during short circuits also the fluctuating decadence of power which can also be termed as power which is dynamic. The tool of Tanner is deployed to evaluate the circuitry, the schema of cell of SRAM is formulated on S Edit & simulation of net list is furnished by making use of T Spice & also assessment of waveforms is done by W Edit. The characterization of circuitry is done by making use of technology of 45 nm which furnish a voltage of 1.2V. The outcomes are put in contrast to traditional 6T SRAM & 7T SRAM which also characterizes the same in this document. Also we implement a cell with less power that is comprised of an additional transistor & also the gate of that transistor will regulate the operations of write & read of information when we implement function of write operation, that additional transistor will execute function of write & additional transistor will shorten the section in ground & Vdd & save the power.

Keyword :- Minimal Power, SRAM, 130nm, 7T SRAM cell.

I. INTRODUCTION

A memory of semiconductor which is also ARAM is a bistate circuitry that is ployed to retain every single bit. The static & dynamic RAM which should be refreshed in a defined period of time. Reminisce is also explained by SRAM but it has volatile nature in a traditional way that means that data will not be retained if memory is turned off.

While commencing the particulars of design to formulation of layout of mask, the design of layout of an integral circuitry have various steps in processing which needed to be focused while execution. The steps invades design of schema at level of transistor, simulation of SPICE at circuitry as per designed proportions of W/L of a distinct transistor, formation of layout by making use of editor of layout, designing check rule, extraction in parasitic manner & exact evaluation & simulation. Such methodologies for processing can't be changed for operations which are free from error & same kind of methodology is deployed for design of IC of SRAM of 1 kilobyte. The cell of SRAM is its main constituent which accumulates one bit of information at a time. The lines of bit that are common can be written & read over cell of SRAM. A standard tool for industry which is SPICE is ployed for purpose of simulation & assessment of cell of SRAM & eventually for complete design. The circuitry which is already charged, the amplifier of sense & circuitry of read & write accomplish memory of one SRAM. The arrangement of matrix is done in form of rows & columns that enhance the addressing of memory in an easy way of bits of memory & also furnish flexibility in design. As the working of array of

cells of memory is evaluated, its imitation can be done for various times by making fewer variations in design in regulatory circuitry of I/O.

II. SRAM CELL: SCHEMATIC AND WORKING

The figure 1 presents memory cell of SRAM for an individual bit. The latches which are static are deployed in cell of SRAM. The cell is formulated from a flip flop that is consisted of inverters which are coupled as cross.

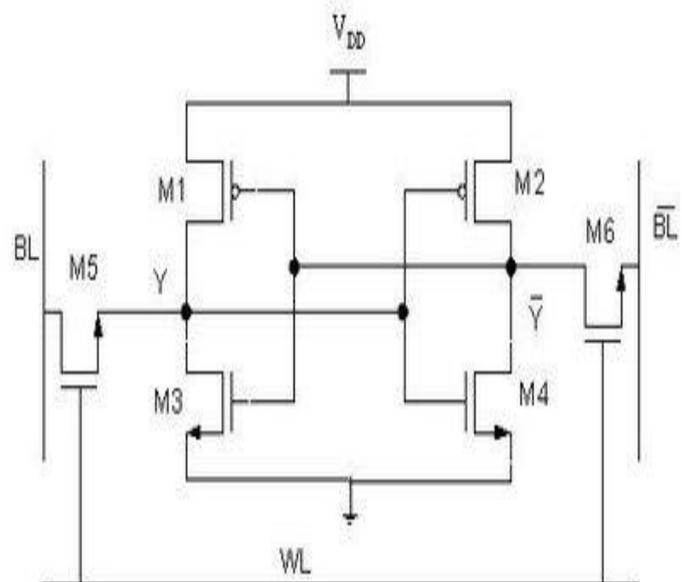


Figure 1 :- Schema for cell of SRAM

The transistors of access which are 2 in number are ployed to evaluate the information retained in cell. The line for control that is WL, word line turns the transistors OFF or ON. In

general, the WL is linked to outcome of circuitry of decoder of row. As the WL is equal to V_{dd}, BL is linked to cell of SRAM & its complementary, which allows both write & read operations. The function of read & write is executed by transistors of access.

READ OPERATION

The Y node is taken as the node for reference for cell of SRAM. As the node of Y at V_{dd} is high, value 1 is stored in cell & bar of Y node retains value 0. For the circumstances that have reverse voltage, cell retains value 0. It is taken that cell retains the value of 0. As the operation of read commences, the lines of BL & BL bar are charged to V_{dd}/2. As by the initiation of WL, the flow of current is by M5 & M6. Though current will flow through V_{dd} by M1 & M5 fluctuating the capacitance of line of bit, like C_{bl}. The present capacitance on line of B_{Lbar} like C_{BLbar} dispenses the transistors by M6 & M4. The process formulates a difference in voltage among the node Y & Y bar which is detected by amplifier to sense value of 1. To parallel to this, value of 0 is sensed by amplifier.

WRITE OPERATION

Here the operation to write value 0 is presumed to store 1 value. By this, amplifiers of sensing & circuitries which are pre charged are disabled. This cell is chosen by triggering the associating signal of WL. In order to write value of 0 to cell, line of BL is taken down to the line of BLbar, which is enhanced to V_{dd} by the circuitry of write. So the Ybar node is raised to V_{dd}/2 eventually Y node is brought down to the same. As the voltage gets over the level on 2 node feedback, action commences. The capacitances are formulated by M4, M6 & M3, M5 which are discharged & charged consequentially. Eventually the Y node is made stable at 1 value. As the capacitances of parasitic are furnished by transistors, which has value much lesser than capacitance of line of bits, and operation of write works fast than read.

III. EXISTING DESIGN DESCRIPTION

SRAM is basically a cell of memory in semiconductor. It accumulates a bit of data. It functions fast & absorbs minimal power in contrast to other cells of memory. As it is robust & has much more stability, more improvisations are being done in cells of SRAM. SRAM is considered as a cardinal element on a microprocessor chip. Formulating a cell of SRAM on a nano scale is formulated as a task that is challengeable as margins in noise are deduced & sensitivity has been raised to fluctuations in voltage of threshold. The cell of 10T-SRAM has better performance than 6T-SRAM on the factors of stability & reliability. Cell of 6T-SRAM is not much reliable

when supply of power is less because margins in noise get degraded.

There are 6 transistors in a cell of 6T-SRAM. The figure 4.1 presents a standard cell. The transistors for access are N2 & N3 and other 4 transistors, N1, N2, P1, P2 formulates 2 inverters. Information is latched by these 2 inverters. The information gets invaded to inverter of latching by transistor of access. The method to introduce information is termed as operation of writing & process to retrieve information is termed as process of reading. A row of cell of SRAM is chosen by WL. A column is chosen by BLbar & BL. A defined cell of SRAM is chosen as BL & WL are turned on. A 6T-SRAM & extra circuitry of reading can formulate cell of 10T-SRAM.

A cell of 10T-SRAM gets designed by making use of cadence virtuoso in technology of CMOS180nm & characteristics of the performance like delay, power, delay in power are assessed.

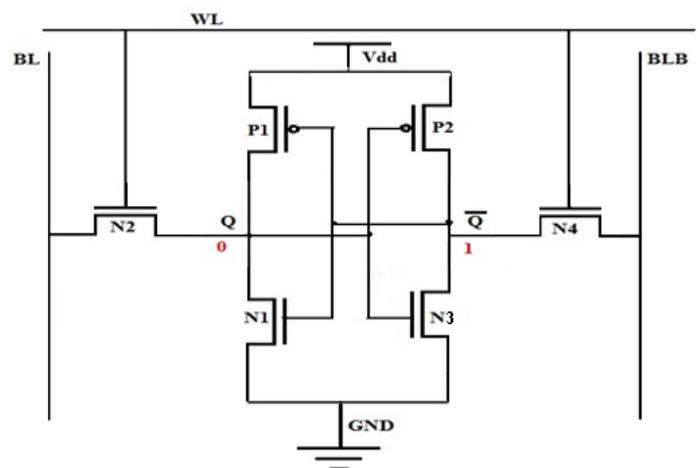


Fig.2 :- A 6T cell of SRAMs

IV. DESIGN AND SIMULATION OF A 10T SRAM CELL

Architecture of cell of 10T-SRAM is alike to cell of SRAM of 6T, but difference is that it has an extra circuitry for read. Figure 2 presents cell of SRAM designed for 10T. In cell of 10T-SRAM, 10 transistors are ployed. It comprise of traditional cells of 6T-SRAM & extra circuitry to read. The issue arises in traditional cells of 6T-SRAM is that there are chances to data to be lost while execution of operation of read. Flipping can occur at voltage at node at Q & Qbar because of inverters aligned back to back.

This problem can be eliminated by putting an additional circuitry. The operations of read in 6T and 10T-SRAM cells are similar. While in scenario of operation of reading, sharing

of charges occurs in RBL & no-transformed BL-BLB while operation of read is executed. As charge are shared, so lines of reading bit don't get discharged fully & remains at a mid level of voltage. Thus, working of cell becomes like an automated limiter for swinging lines of bit.

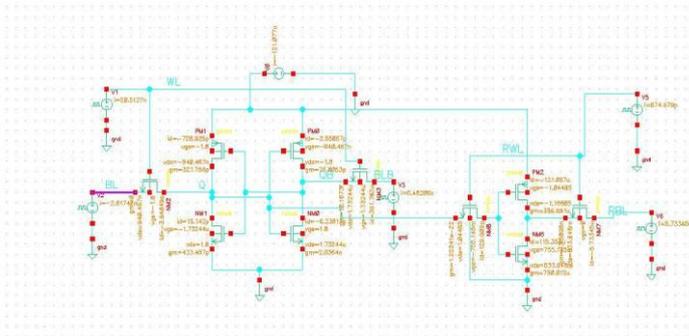


Fig.3:- Design of a 10T SRAM cell

STANDBY MODE

If insertion of WL is not done, transistors of Paas will be de-linked from lines of bit & cell. The inverters which are coupled cross formulate two inverters linked to each other in an adjoined manner. They reinforce one & other as they been de-lined from outer world. The data which is accumulated in the cell of their memory will be retained in them.

READ MODE

It is presumed that memory accumulates 1 which is stores at a node. The cycle of read commence as both lines of bit gets pre charged to logical value 1 & embedding the signal of WL with a pulse of high voltage that triggers both transistors of access. In next step, as values are accumulated in a & B which gets transferred to lines of bit, one BL will discharge transistor drivers & other BL will get pulled by transistor of load in direction of VDD that is logical 1. The process would have worked in opposite manner if memory has accumulated 0 & cell of memory would be at logical 1.

WRITE MODE

Commencement of cycle of writing starts when the values that are written to BL are applied. If 0 is to be written, so same will be applied to BLs which means putting BL=0 & BLbar=1. It is just like to apply a pulse set to latch of SR that fluctuate state of flip flop. As the values of BL are inverted, 1 is written over it. Assertion of WL is done & values that are to be accumulated are latched. The factor that causes this is that input drivers of BL are formulated in such a manner to be strong than a related transistor in a cell by its own, in a case that previous states can be over-riden of inverters which are coupled cross. A concentrated sizing of transistor in cell of

SRAM is requires to get assurance of actual operation. In this document, a cell of SRAM suggested that incorporates an additional transistor in way of pull down of both transistor of driver. This additional transistor will disconnect way in transistor driver & GND while execution of operation of writing that decrease aggregated capacitance & power which is dynamic. The suggested cell of SRAM is applied & designed by making use of technology of CMOS of 130 nm. Lastly, outcomes are put in contrast with traditional cell of 6T-SRAM which is signified in the theory of similar technology.

V. PROBLEM STATEMENT

In a standard circuitry of 6T-SRAM, absorption of power is greater because of additional current flow. As by image, generally circuitry of 6T-SRAM is played in a standard circuit. In a case, as function of reading will be initiated, then flow of leakage in power is in operation of writing in circuitry. In further scenario, when operation of write is executed in circuitry, operation of reading will be off but a bit power flow will be there. And because of this leakage in power, there will be improvisation in absorption of power. So we will focus to eliminate the leak in absorption of power.

VI. PROPOSED METHODOLOGY

PROPOSED 7T SRAM CELL

The given Figure 4 presents schema of cell of SRAM with less power & signals related to it wherever, CS, WL are required for making a selection for writing & data can be written from bit bar & bar.

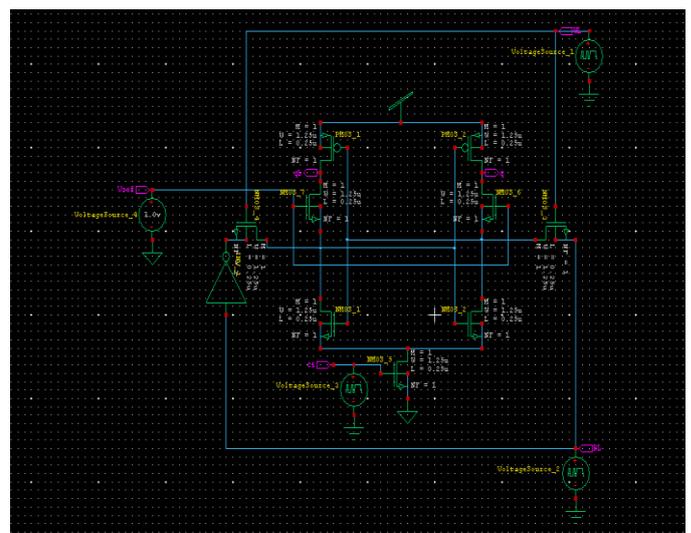


Figure 4 :- Proposed Circuit

As represented by Figure 4, cell with minimal power is comprised of an additional transistor & gate of that additional transistor will regulate operation of reading or writing information & also when operation of write is executed as the additional transistor cuts down the path in Vdd & ground & save circuitry from short circuit. We can make use of input, bit data or its complementary to execute operation of writing. Functioning of cell of SRAM with less power & operation is explained in the modes of write & read as below:

READ MODE

Generally, cell of SRAM with less power in mode of reading is alike to traditional cell of SRAM. In this mode, value 1 is assigned to CS & an additional transistor will be activated on the basic operation of reading for cell of SRAM when a high voltage is provided to WLs, both the transistors of access will get activated & data needed will be out by the sensing amplifier.

WRITE MODE

In mode of writing, node of B should be assigned higher value which is achieved by putting CS as 0 invading signals of WL value of data is implemented to BL. There may be a possibility to write state of cell from 1 to 1. As nodes of B & CS, both are 0, no transition in state occurs. As conductance of N4 transistor has greater conductance than P2, the state of cell is flipped easily from 0 to 1 as node B is discharged by N4. As data can be written from 0 to the corresponding path as presented in figure 6.

VII. RESULTS

6T CONVENTIONAL CIRCUIT

In this circuitry, we deploy transistors 6 in numbers. BL & WL is defined for write & read operations. The absorption of power for figure 6.1 is 7.028097e-006 W & delay is 1.34ns.

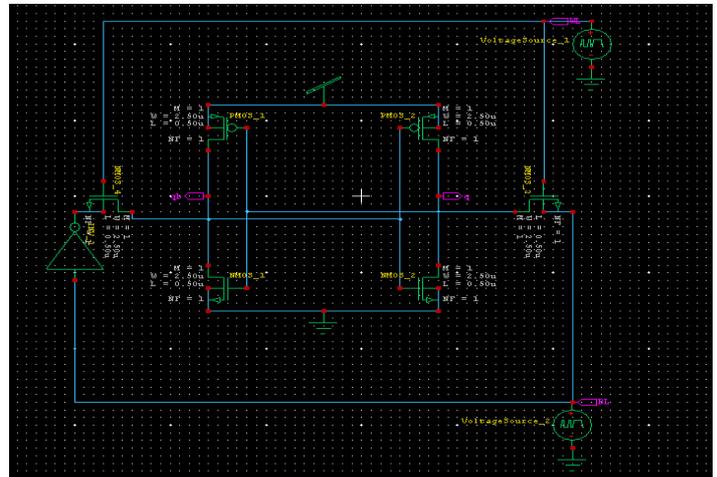


Fig 6 :- 6T traditional circuitry

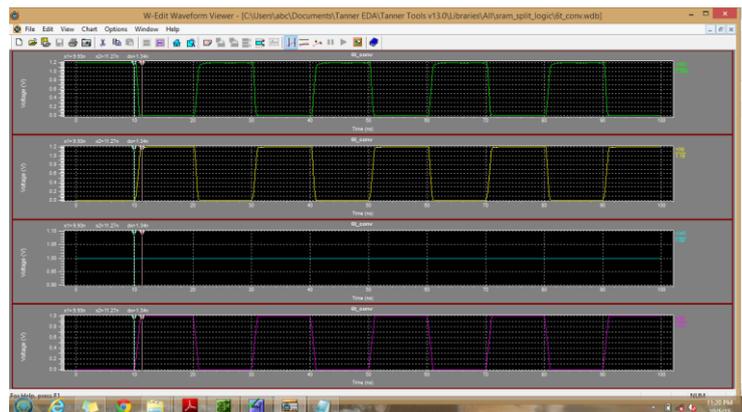


Fig 7 :- Waveform of 6T traditional circuitry

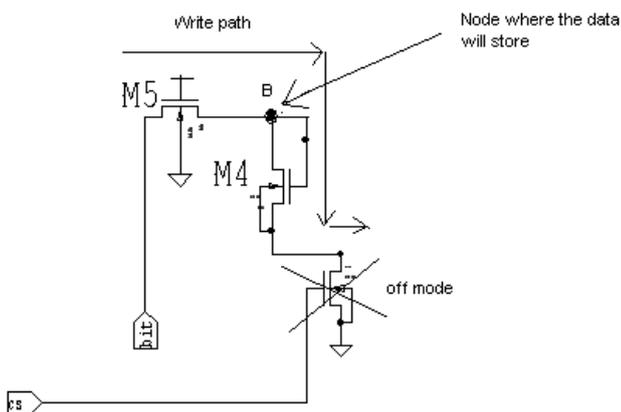


Fig 5:- suggested circuitry in mode of writing

Parallel, 0 will be written in cell of SRAM at less power. The path of circuitry is presented in figure.

7T SRAM DESIGN

The absorption of power in figure 6.2 is 4.446633e-006W & delay is 1.18ns.

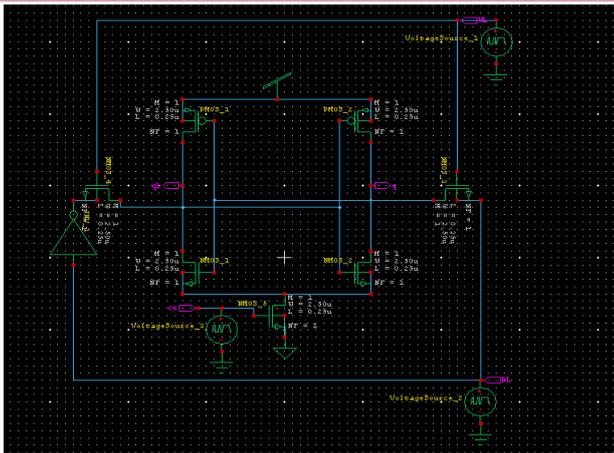


Fig 8:- 7T SRAM Design with implementation of circuitry of CS

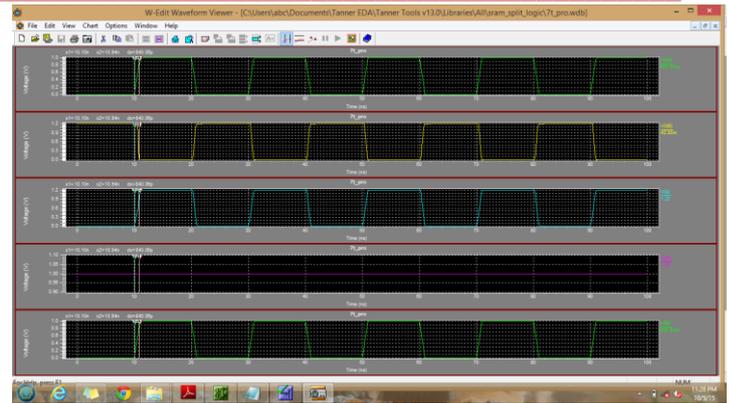


Fig 11 :- Outcome of waveform for suggested 7T SRAM

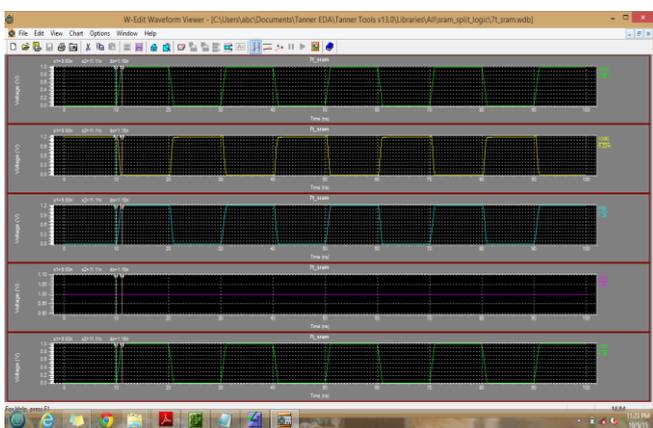


Fig 9 :- Waveform for design of 7T SRAM

PROPOSED 7T SRAM DESIGN

The absorption of power for design of 7T SRAM is 4.184023e-006W with delay of 840.06ps.

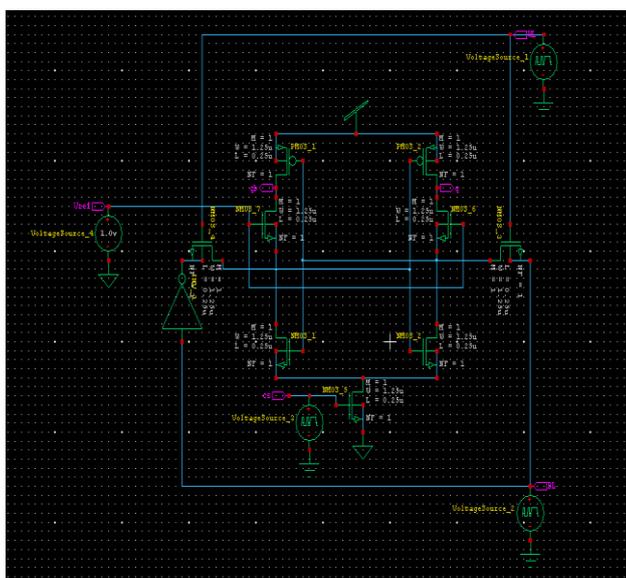


Fig 10 :- Suggested design of 7T SRAM

	Power	Delay
Reference paper [1]	4.6 micro watt	Not mention
Reference paper [2]	81 micro watt	7.5 ns
Reference paper [3]	50 micro watt	5.5 ns
Existing SRAM design	7.028097 micro watt	1.34 ns
Proposed SRAM Design	4.184023e-006 watts	840.06 ps

Table 1 :- Table of Contrast

VIII. CONCLUSION AND FUTURE SCOPE

As observations from outcomes reveal that in cells of SRAAM with less power, aggregated power gets brought down by 43%. It presents that cell of memory will absorb low power in contrast to traditional cells of SRAM whose outcomes are imitated in this document. In a situation of power with short circuits, decadence of power gets down by 43% that is less in contrast to traditional cells of SRAM. Thus, the cell of SRAM which is newly formulated absorbs low power & it can be said that it is aware of power that can be accepted in the present market of VLSI. The delay is also improved by 74%. So, cell of SRAM absorbs low power & executes operation faster than a standard cell of SRAM. In this cell lesser amount of power is taken in & so it saves around 43% of power in contrast to the present cells of SRAM. Thus these cells are deployed in electronics which are portable & are operated by battery & so will need low cost sink of heat to furnish heat to surroundings.

This documentation can be elaborated for future work in order to bring down need of area that is around 16.72 % greater than the present cell of SRAM. A methodology can be searched to reduce this area & also there are no improvisations in cells of low power when operation to write 1 is executed & so work can be extended for improvisation in delay whenever, operation of writing is executed.

References

- [1] Saravanan, P., and Kalpana, P., "A 16nm SRAM design for low power and high read stability", 3rd International Conference on Advances in Recent Technologies in Communication and Computing, Bangalore, pp. 25-31, 2011.
- [2] Verma, N., Chandrakasan, A. P., "A 256kb 65nm 8T Subthreshold SRAM Employing Sense Amplifier Redundancy", IEEE Journal of Solid State Circuits, Vol. 43, No. 1, pp.141-149, 2008.
- [3] Athe, P., and Dasgupta, S., "A Comparative Study of 6T, 8T and 9T Decanano SRAM cell", IEEE Symposium on Industrial Electronics and Applications, Kuala Lumpur, pp. 889-894, 2009.
- [4] Sah, R. K., Hussain, I., and Kumar, M., "Performance Analysis of a 6T SRAM Cell in 180nm CMOS Technology", IOSR Journal of VLSI and Signal Processing, Vol. 5, Issue 2, Ver. 1, pp. 20-22, 2015.
- [5] Sah, R. K., Hussain, I., and Kumar, M., "Performance Comparison for Different Configurations of SRAM Cells", International Journal of Innovative Research in Science, Engineering and Technology, Vol. 4, Issue 1, pp. 18543-18546, 2015.
- [6] Jain, S., Santhosh, K., Pattanaik, M., and Raj, B., "A 10T SRAM cell with inbuilt charge sharing for Dynamic power Reduction", International conference on Advances in technology and Engineering, Mumbai, pp. 1-6, 2013.
- [7] Chang, I. J., Mohapatra, D., and Roy, K., "A Priority-Based 6T/8T Hybrid SRAM Architecture for Aggressive Voltage Scaling in Video Applications", IEEE Transactions On Circuits And Systems For Video Technology, Vol. 21, No. 2, pp.101-112, 2011.
- [8] Prashant Upadhyay, Mr. Rajesh Mehra, "Low Power Design of 64-bits Memory by using 8-T Proposed SRAM Cell", International Journal of Research and Reviews in Computer Science (IJRRCS), Vol. 1, No. 4, December 2010.
- [9] Sreerama Reddy G.M, P. Chandrashekara Reddy, "Design and VLSI Implementation of 8 Mb Low Power SRAM in 90nm", European Journal of Scientific Research, Vol. 26, No. 2, pp. 305-314, 2009.
- [10] Keejong Kim, Hamid Mahmoodi, "A Low-Power SRAM Using Bit-Line Charge-Recycling", IEEE Journal Of Solid-State Circuits , Vol. 43, No. 2, 2008.
- [11] K. Itoh, K. Sasaki, Y. Nakagome, "Trends in low-power RAM circuit technologies", in Dig. Tech. Papers, 1994 Symp. Low Power Electronics, 1994, pp. 84-87.
- [12] Chang, Y., Lai, F., Yang, C., "Zero-aware symmetric SRAM cell for reducing cache power in writing zero", IEEE Trans. VLSI Systems, Vol. 12, No. 8, pp. 827-36, 2004.
- [13] J. L. Hennessy, D. A. Patterson, "Computer Architecture: A Quantitative Approach", 2nd ed. San Mateo, CA: Morgan Kaufmann, 1995.
- [14] S. Kang, Y. Leblebici, "CMOS Digital Integrated Circuits", New York, McGraw-Hill, 1999.
- [15] Sreenivasa Rao Ijjada, B.Rampamesh, Dr. V.Malleswara Rao, "Reduction of Power-Dissipation in Logic Circuits", International Journal of Computer Applications, Vol. 24, No. 6, 2011.